

The invention relates to the field of measuring equipment and can be used in measuring devices that use nanosensors based on nanostructured semiconductor oxides.

The device for measuring the parameters of sensors based on micro- and nanostructured semiconductor oxides comprises a reference voltage source (U_{ref}), which voltage is applied to the input of one of the analog-to-digital converters (ADC) of a microcontroller (MCU) via an operational amplifier, and which is connected in series to the investigated nanostructure (R_x) and an additional resistor (R_0), and the voltage drop across the resistor (R_0) is applied to the input of a second analog-to-digital converter (ADC) of the microcontroller (MCU) via the second operational amplifier. The output of the microcontroller (MCU) is connected to a screen for displaying the results obtained.

Claims: 1

Fig.: 2

